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INTERNATIONAL STANDARD

**Fibre optic communication subsystem test procedures –
Part 2-3: Digital systems – Jitter and wander measurements**

INTERNATIONAL
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INTERNATIONAL ELECTROTECHNICAL COMMISSION

FIBRE OPTIC COMMUNICATION SUBSYSTEM TEST PROCEDURES –

Part 2-3: Digital systems – Jitter and wander measurements

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International Standard IEC 61280-2-3 has been prepared by subcommittee 86C: Fibre optic systems and active devices, of IEC technical committee 86: Fibre optics.

The text of this standard is based on the following documents:

FDIS	Report on voting
86C/885/FDIS	86C/905/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

A list of all parts of the IEC 61280-2 series, published under the general title *Fibre optic communication subsystem test procedures – Digital systems*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual version may be published at a later date.

FIBRE OPTIC COMMUNICATION SUBSYSTEM TEST PROCEDURES –

Part 2-3: Digital systems – Jitter and wander measurements

1 Scope

This part of IEC 61280 specifies methods for the measurement of the jitter and wander parameters associated with the transmission and handling of digital signals.

1.1 Types of jitter measurements

This standard covers the measurement of the following types of jitter parameters:

- a) jitter tolerance
 - 1) sinusoidal method
 - 2) stressed eye method
- b) jitter transfer function
- c) output jitter
- d) systematic jitter
- e) jitter separation

1.2 Types of wander measurements

This standard covers the measurement of the following types of wander parameters:

- a) non-synchronized wander
- b) TDEV tolerance
- c) TDEV transfer
- d) synchronized wander

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60825-1, *Safety of laser products – Part 1: Equipment classification and requirements*

ITU-T Recommendation G.813, *Timing characteristics of SDH equipment slave clocks (SEC)*